

RELIABILITY DATA

LT1620 / LT1621

10/26/2003

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
SSOP/TSSOP	36	9813	9813	36.09	0
	36			36.09	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	4,388	9636	0010	724.11	0
SSOP/TSSOP	794	9746	0212	30.80	0
	5,182			754.92	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	7,196	9637	0051	1,533.06	0
SSOP/TSSOP	804	9746	0212	80.70	0
	8,000			1,613.76	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,640	9637	0009	953.28	0
SSOP/TSSOP	681	9752	0212	68.10	0
	3,321			1,021.38	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 50.97 FITS

(3) Mean Time Between Failures in Years = 2,238

Note: 1 FIT = 1 Failure in One Billion Hours.